

# **ECE 551**

# **System on Chip Design**

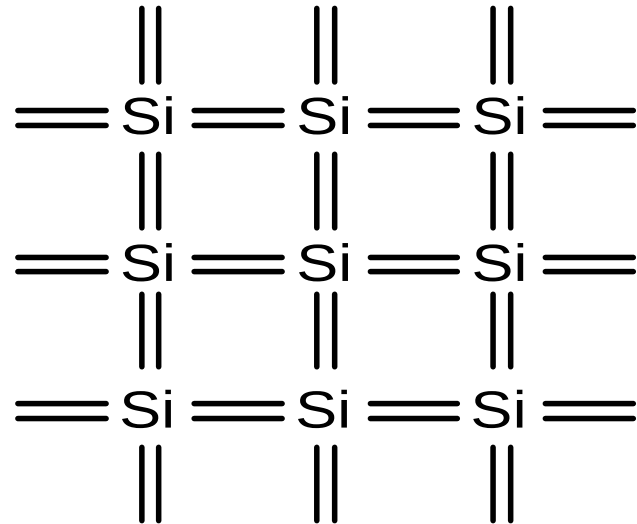
**Crash Course: VLSI Devices & Circuits**

**Garrett S. Rose**  
**Fall 2018**

# The Silicon Lattice

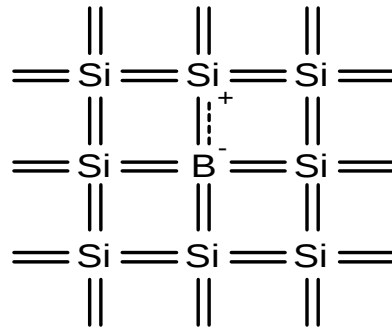
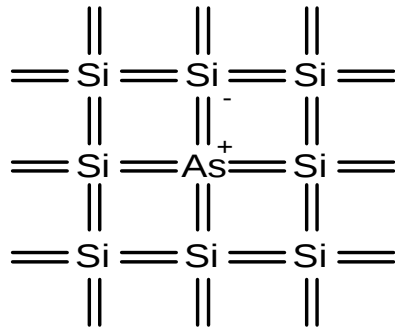
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- Transistors are built on a silicon substrate
- Silicon is a Group IV material
- Forms crystal lattice with bonds to four neighbors



# Device Engineering: The Roll of Dopants

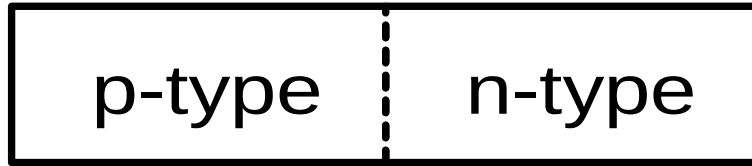
- Silicon is a semiconductor
- Pure silicon has no free carriers and conducts poorly
- Adding dopants increases the conductivity
- Group V: extra electron (n-type)
- Group III: missing electron, called hole (p-type)



# The p-n Junction

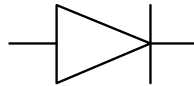
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- Junction between p-type & n-type semiconductor forms diode.
- Current flows only in one direction



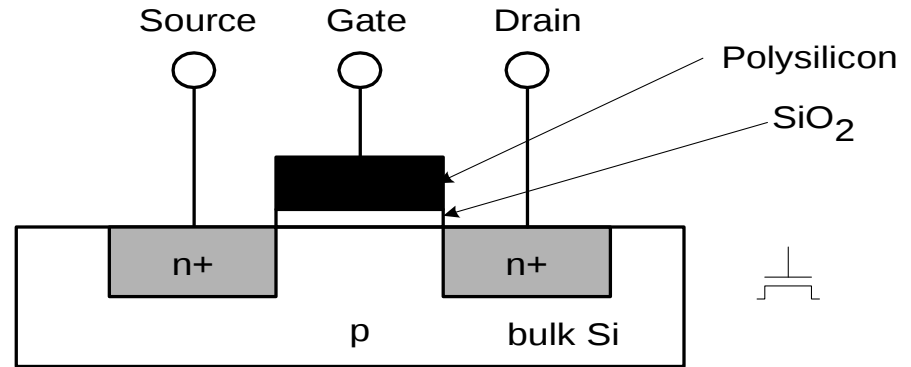
anode

cathode



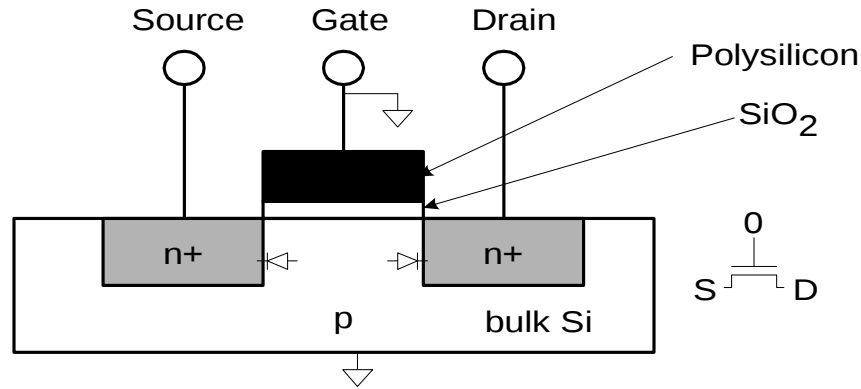
# NMOS Transistor

- Four terminals: gate, source, drain, body
- Gate – oxide – body stack looks like a capacitor
  - Gate and body are conductors
  - $\text{SiO}_2$  (oxide) is a very good insulator
  - Called metal – oxide – semiconductor (MOS) capacitor
  - Even though gate is no longer made of metal



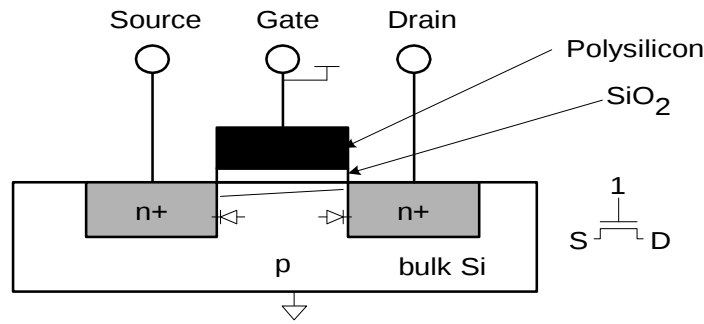
# NMOS Operation

- Body is commonly tied to ground (0 V)
- When the gate is at a low voltage:
  - P-type body is at low voltage
  - Source-body and drain-body diodes are OFF
  - No current flows, transistor is OFF



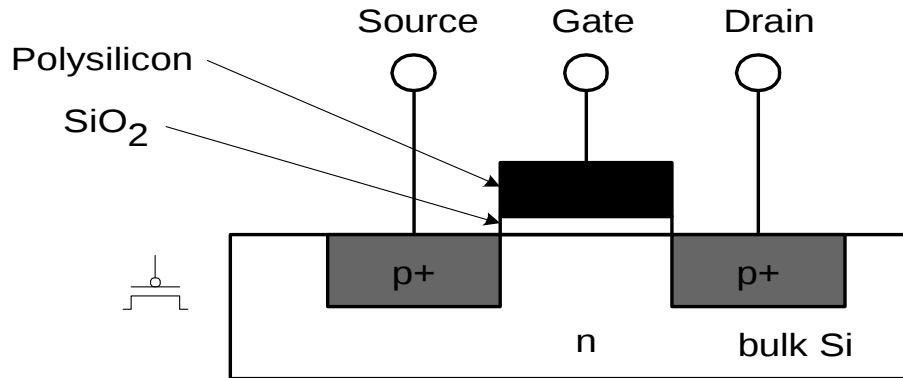
# NMOS Operation

- When the gate is at a high voltage:
  - Positive charge on gate of MOS capacitor
  - Negative charge attracted to body
  - Inverts a channel under gate to n-type
  - Now current can flow through n-type silicon from source through channel to drain, transistor is ON



# PMOS Transistor

- Similar, but doping and voltages reversed
  - Body tied to high voltage ( $V_{DD}$ )
  - Gate low: transistor ON
  - Gate high: transistor OFF
  - Bubble indicates inverted behavior





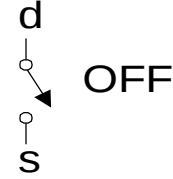
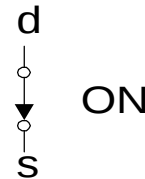
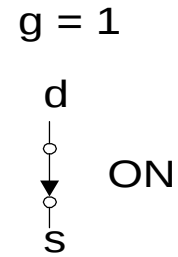
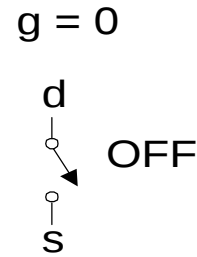
# Supply Voltage

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- $GND = 0\text{ V}$
- In 1980's,  $V_{DD} = 5\text{V}$
- $V_{DD}$  has decreased in modern processes
  - High  $V_{DD}$  would damage modern tiny transistors
  - Lower  $V_{DD}$  saves power
- $V_{DD} = 3.3, 2.5, 1.8, 1.5, 1.2, 1.0, \dots$

# Transistors as Switches

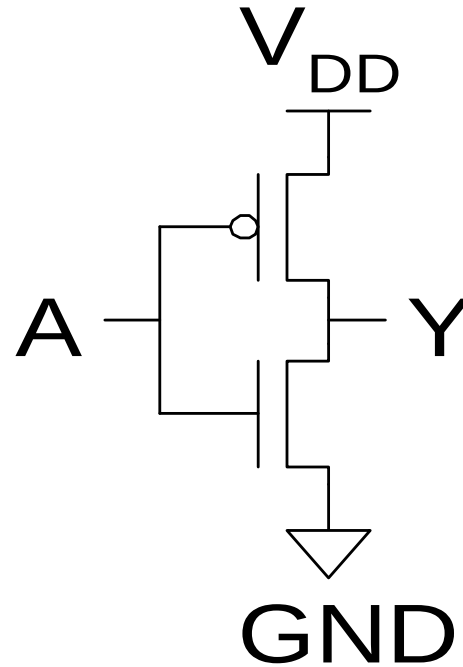
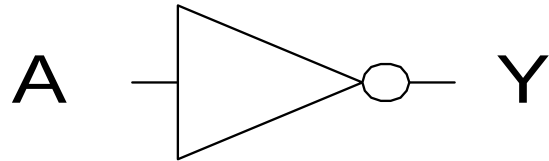
- We can view MOS transistors as electrically controlled switches
- Voltage at gate controls path from source to drain



# Foundation: The CMOS Inverter

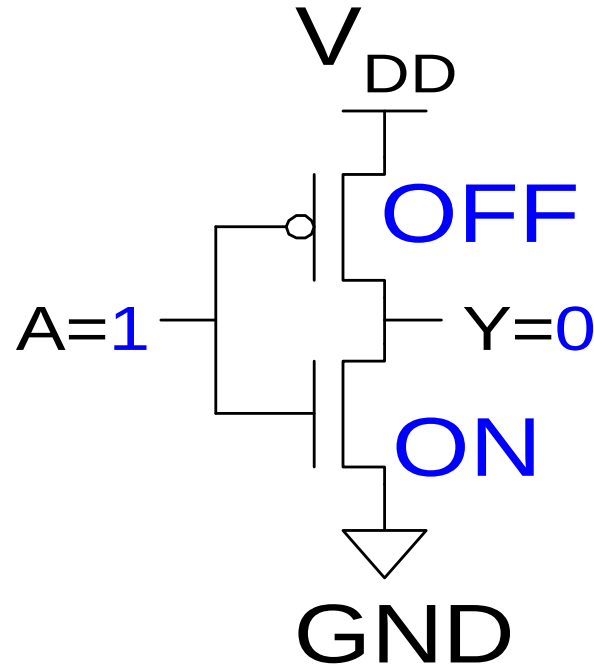
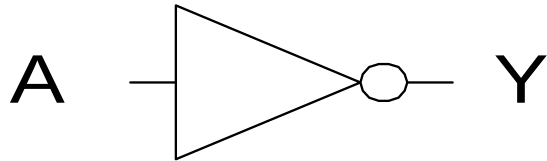
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A	Y
0	
1	



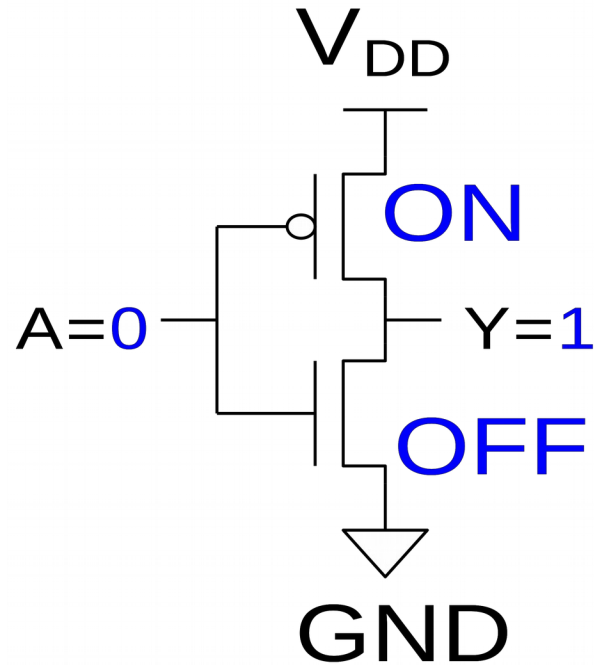
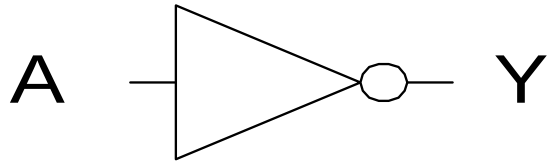
# Foundation: The CMOS Inverter

A	Y
0	
1	0



# Foundation: The CMOS Inverter

A	Y
0	1
1	0

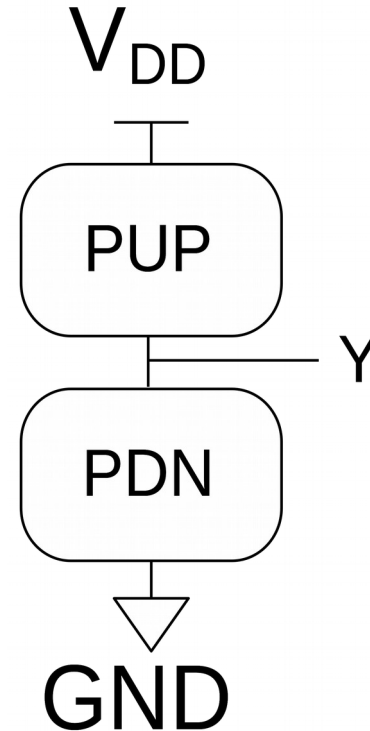


# More Complex Circuits:

## Pull-Up and Pull-Down Networks

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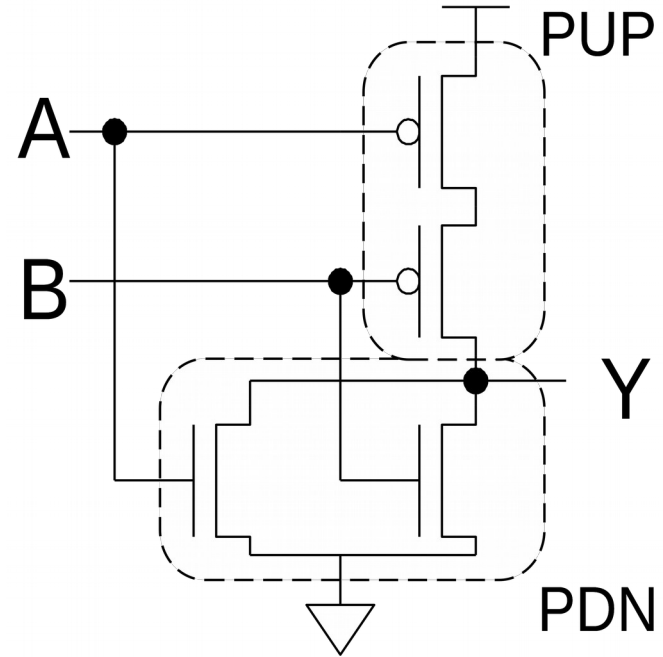
- Pull-up net (PUP) off when pull-down (PDN) on
- PUP implemented as complement of PDN (Complementary MOS)
- If two FETs in parallel in PDN, counterparts in series in PUP
- Output (Y) connected to VDD or GND, never both



# More Complex Circuits:

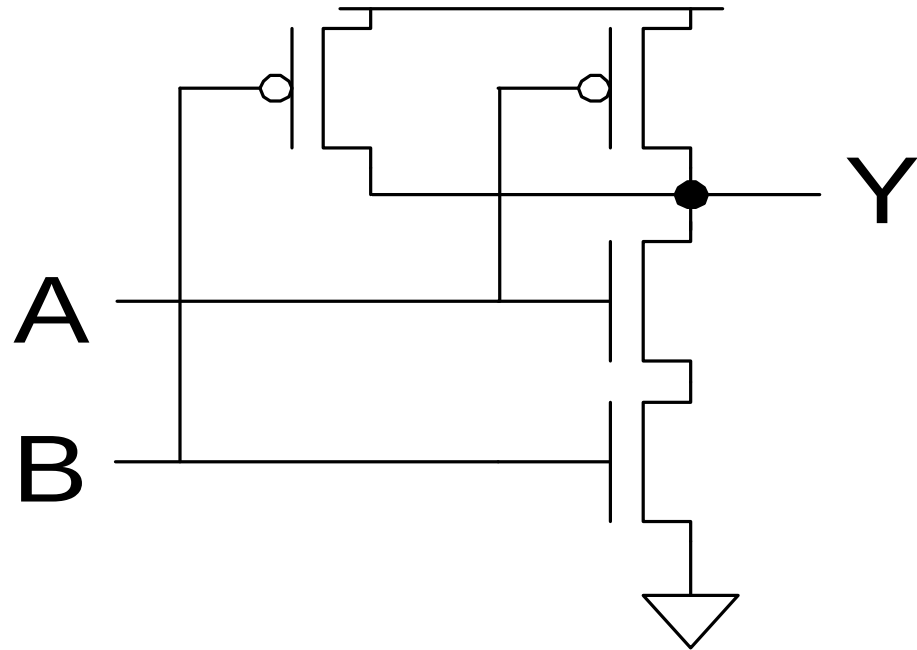
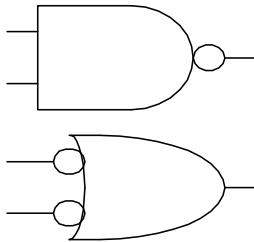
## Pull-Up and Pull-Down Networks

- Pull-up net (PUP) off when pull-down (PDN) on
- PUP implemented as complement of PDN (Complementary MOS)
- *If two FETs in parallel in PDN, counterparts in series in PUP*
- Output (Y) connected to VDD or GND, never both



# Foundation: The CMOS NAND Gate

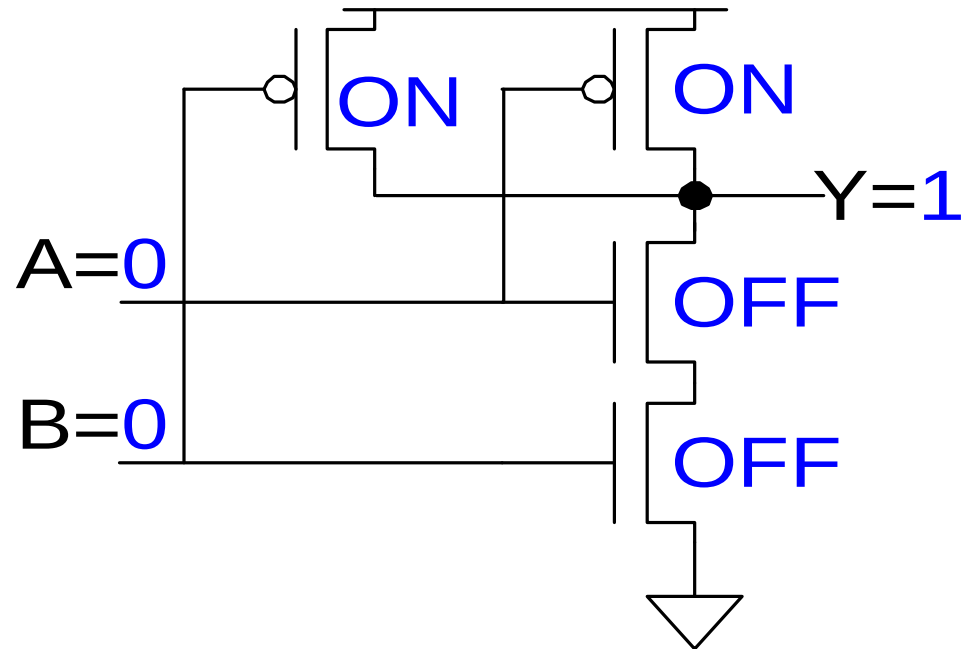
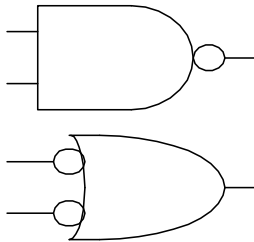
A	B	Y
0	0	
0	1	
1	0	
1	1	





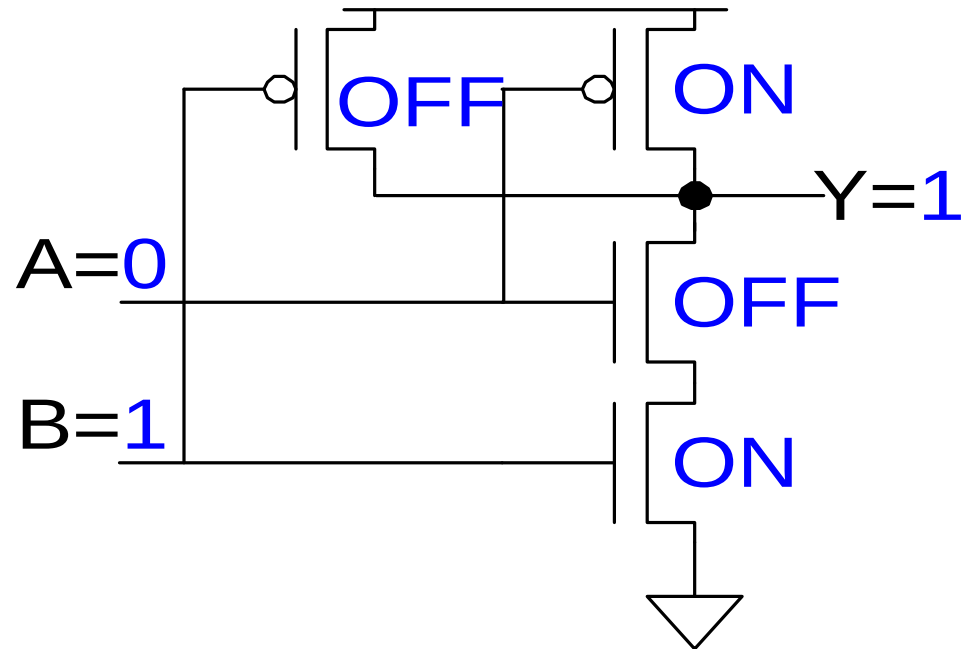
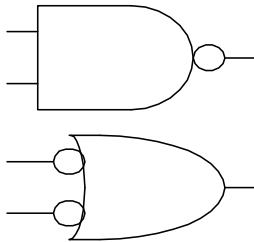
# Foundation: The CMOS NAND Gate

A	B	Y
0	0	1
0	1	
1	0	
1	1	



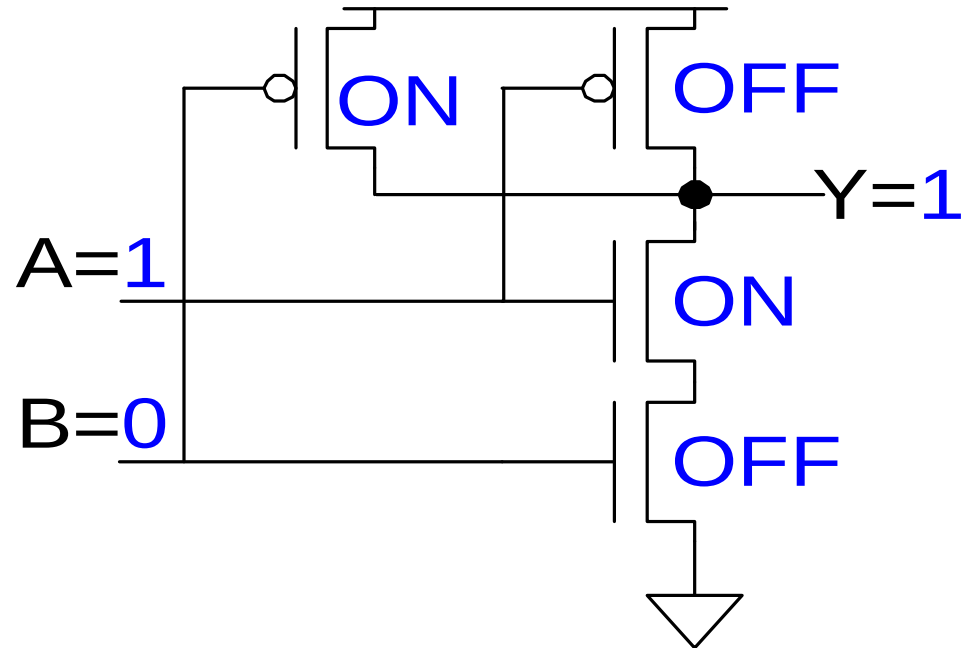
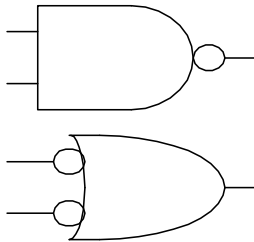
# Foundation: The CMOS NAND Gate

A	B	Y
0	0	1
0	1	1
1	0	
1	1	



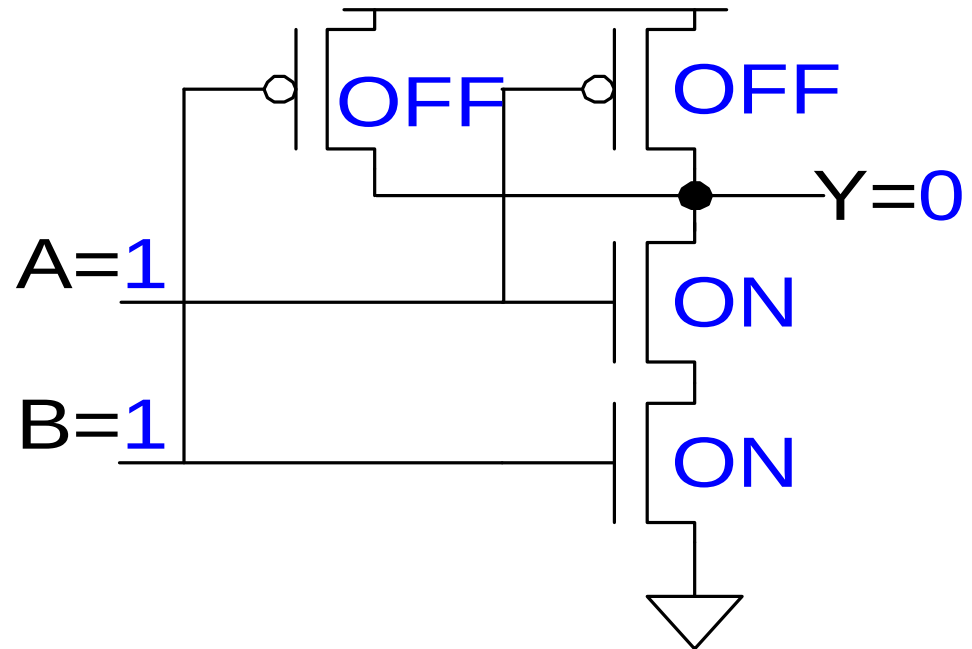
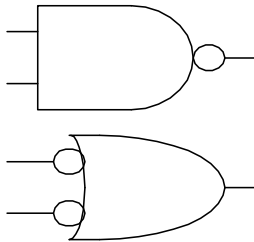
# Foundation: The CMOS NAND Gate

A	B	Y
0	0	1
0	1	1
1	0	1
1	1	



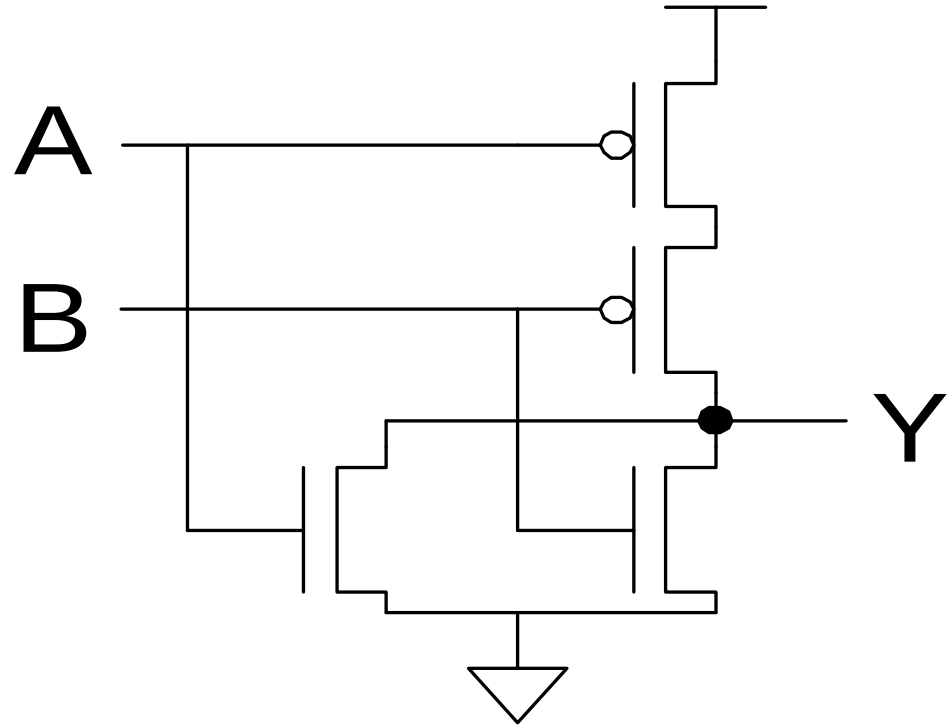
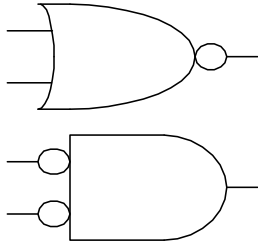
# Foundation: The CMOS NAND Gate

A	B	Y
0	0	1
0	1	1
1	0	1
1	1	0



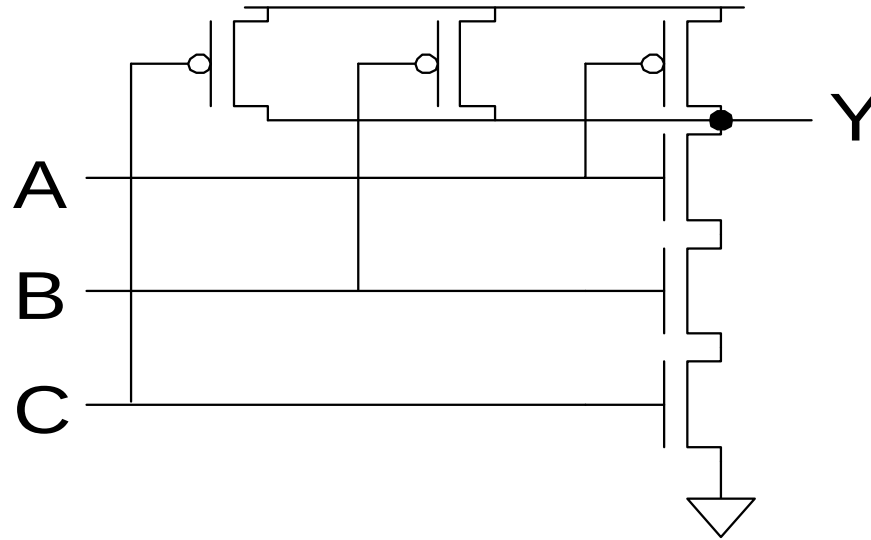
# Foundation: The CMOS NOR Gate

A	B	Y
0	0	1
0	1	0
1	0	0
1	1	0



# Building Up: A 3-Input NAND Gate

- Y pulls low if ALL inputs are 1
- Y pulls high if ANY input is 0



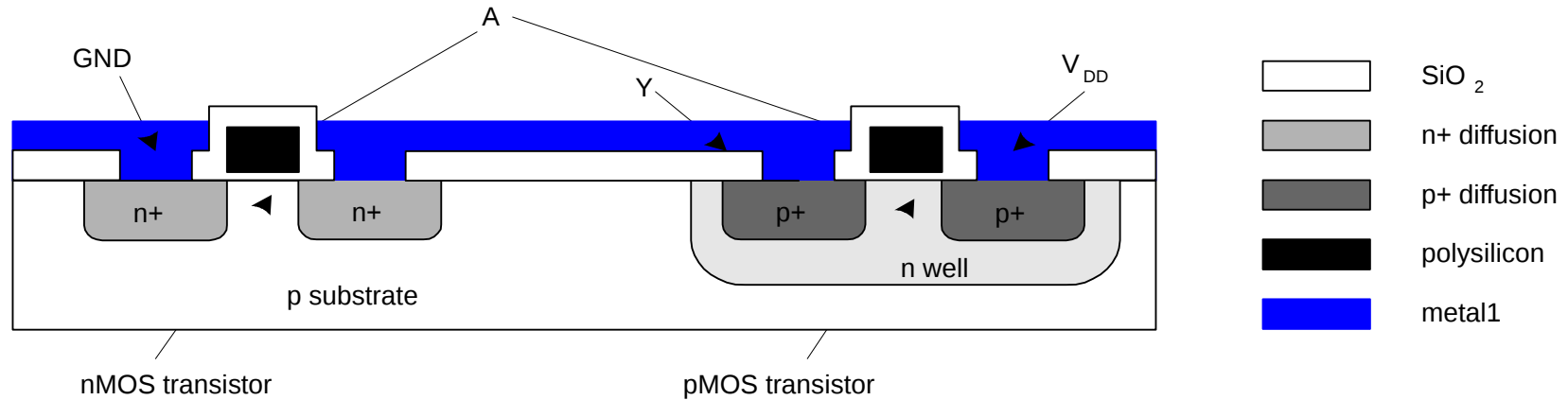
# CMOS Fabrication

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- CMOS transistors are fabricated on silicon wafer
- Lithography process similar to printing press
- On each step, different materials are deposited or etched
- Easiest to understand by viewing both top and cross-section of wafer in a simplified manufacturing process

# CMOS Inverter Cross-Section

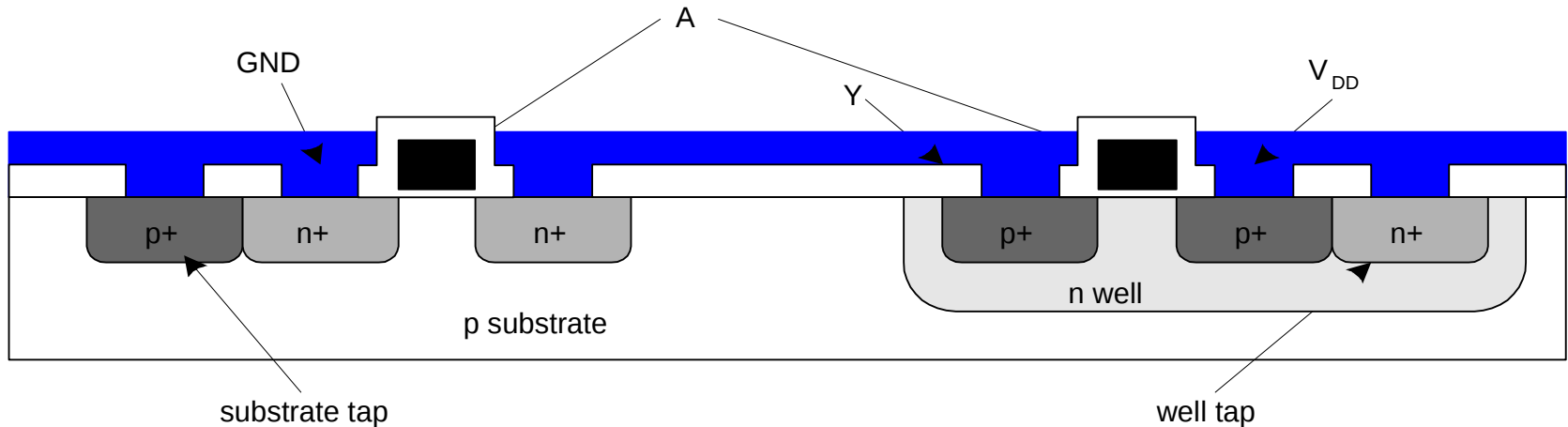
- Typically use p-type substrate for nMOS transistors
- Requires n-well for body of pMOS transistors





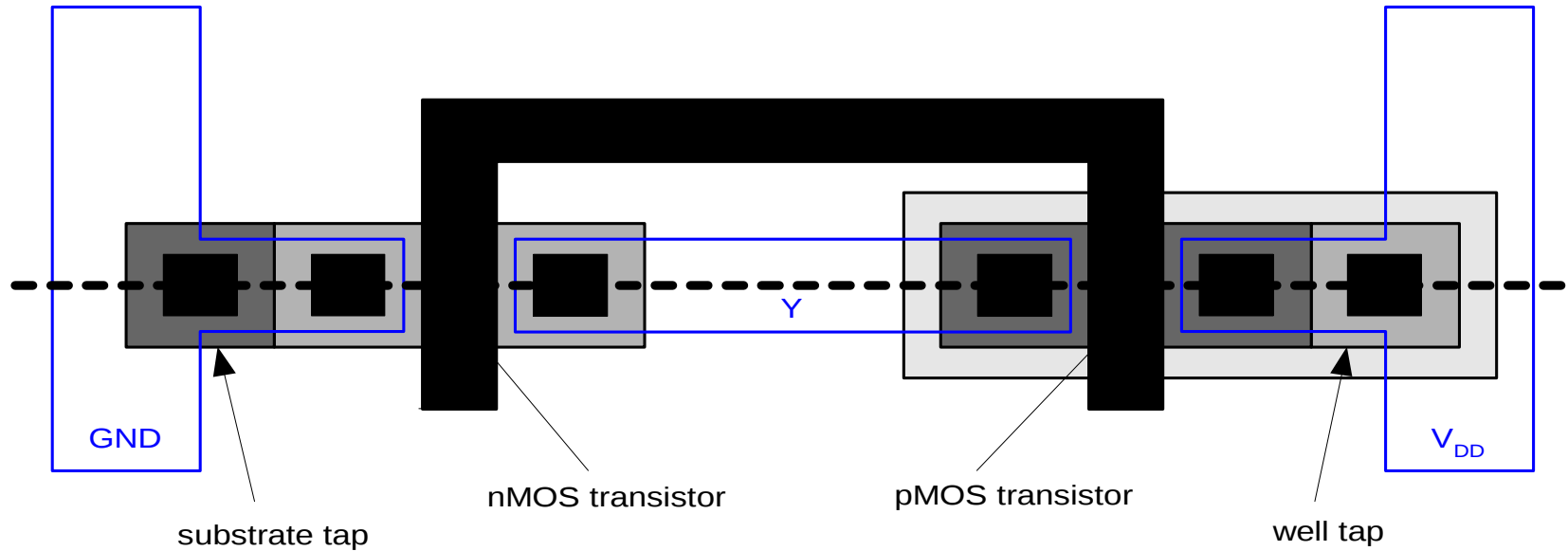
# Well and Substrate Taps

- Substrate must be tied to GND and n-well to  $V_{DD}$
- Metal to lightly-doped semiconductor forms poor connection called Shottky Diode
- Use heavily doped well and substrate contacts / taps



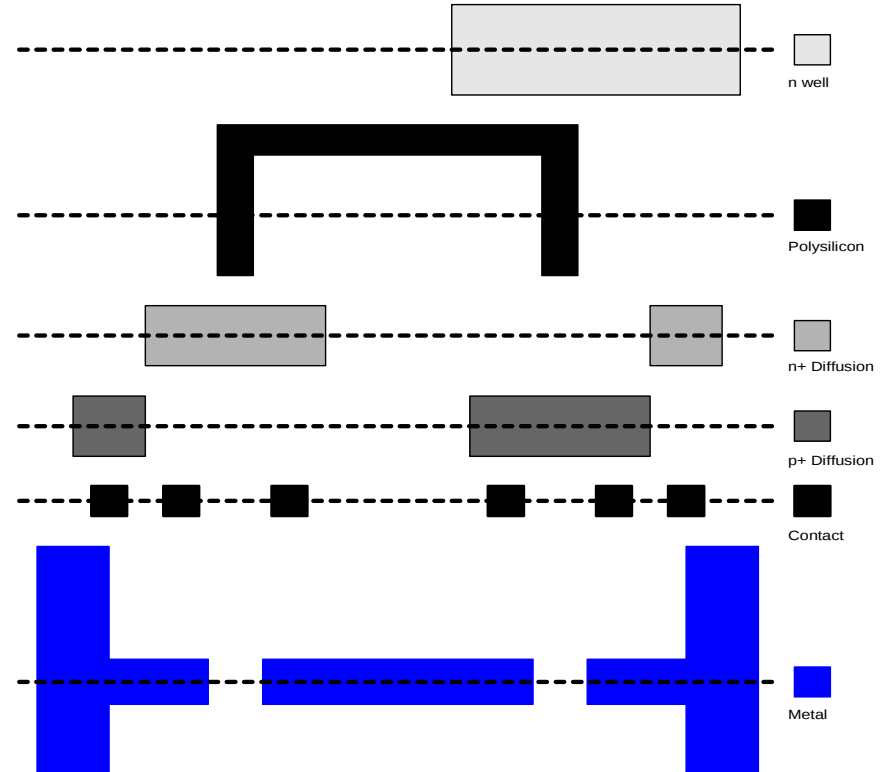
# Example Inverter Mask Set

- Transistors and wires are defined by *masks*
- Cross-section taken along dashed line



# Detailed Mask Views

- Six masks
  - n-well
  - Polysilicon
  - n+ diffusion
  - p+ diffusion
  - Contact
  - Metal



# Fabrication Steps

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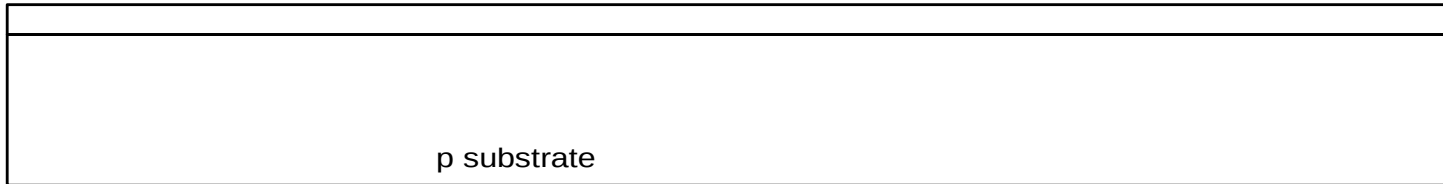
- Start with blank wafer
- Build inverter from the bottom up
- First step will be to form the n-well
  - Cover wafer with protective layer of  $\text{SiO}_2$  (oxide)
  - Remove layer where n-well should be built
  - Implant or diffuse n dopants into exposed wafer
  - Strip off  $\text{SiO}_2$

p substrate

# Fab Step: Oxidation

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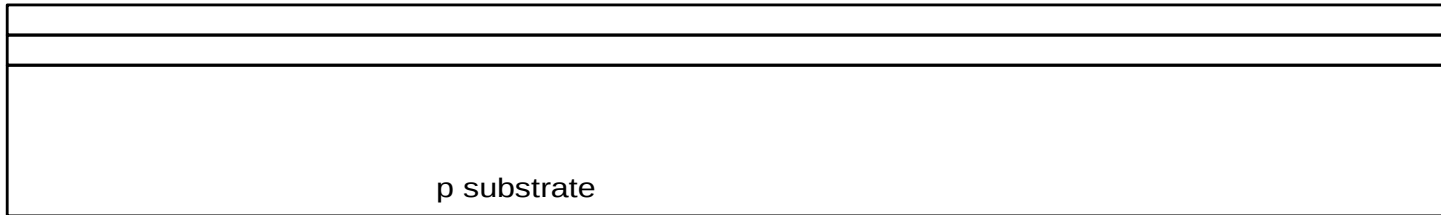
- Grow  $\text{SiO}_2$  on top of Si wafer
  - 900 – 1200 C with  $\text{H}_2\text{O}$  or  $\text{O}_2$  in oxidation furnace



# Fab Step: Add/Spin Photoresist

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- Spin on photoresist
  - Photoresist is a light-sensitive organic polymer
  - Softens where exposed to light

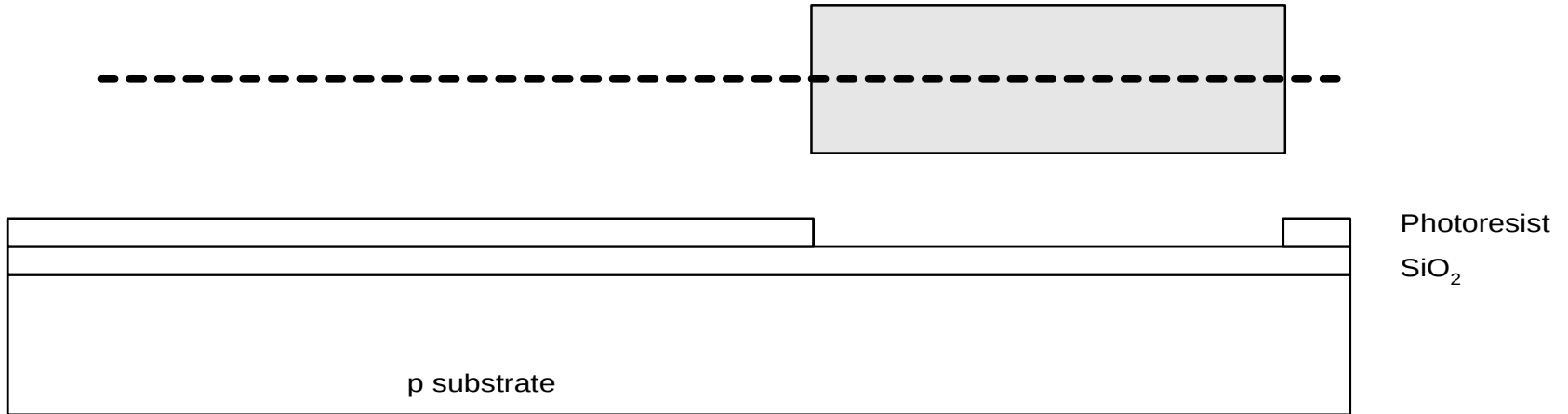


Photoresist  
SiO<sub>2</sub>

# Fab Step: Lithography

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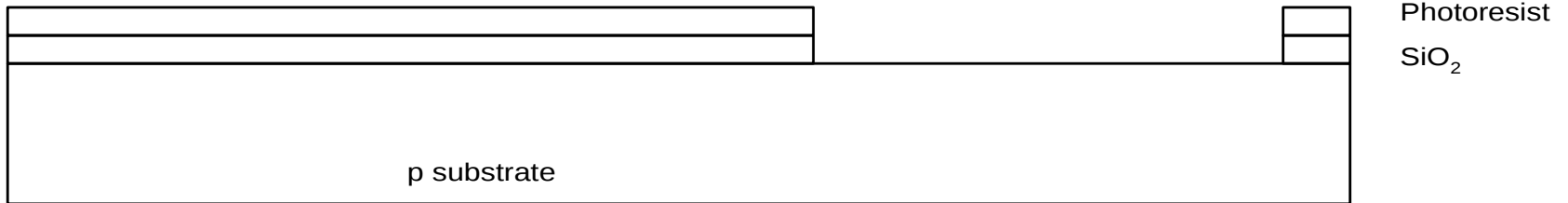
- Expose photoresist through n-well mask
- Strip off exposed photoresist



# Fab Step: Etch

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- Etch oxide with hydrofluoric acid (HF)
  - Seeps through skin and eats bone; nasty stuff!!!
- Only attacks oxide where resist has been exposed

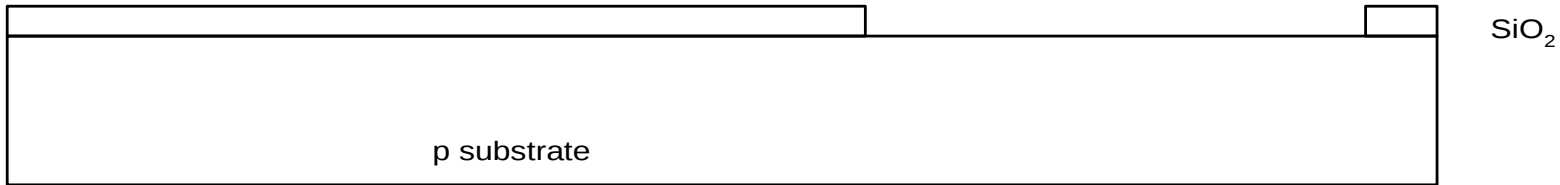




# Fab Step: Strip Photoresist

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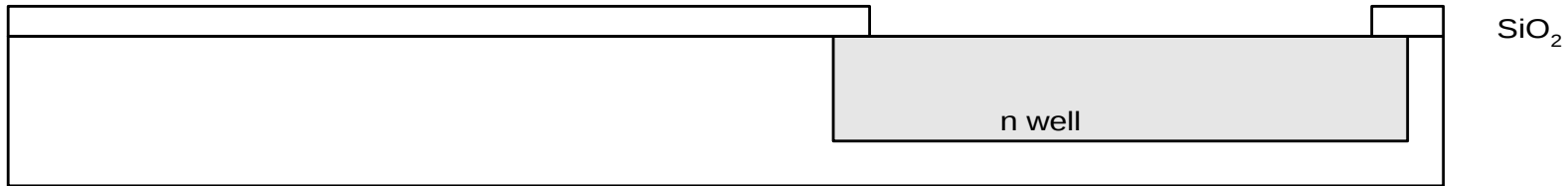
- Strip off remaining photoresist
  - Use mixture of acids called piranha etch
- Necessary so resist doesn't melt in next step



# Fab Step: N-Well Formation

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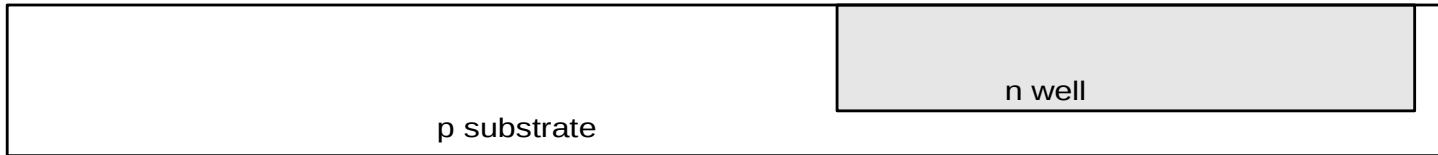
- n-well is formed with diffusion or ion implantation
- Diffusion
  - Place wafer in furnace with arsenic gas
  - Heat until As atoms diffuse into exposed Si
- Ion Implantation
  - Blast wafer with beam of As ions
  - Ions blocked by  $\text{SiO}_2$ , only enter exposed Si



# Fab Step: Strip Oxide

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- Strip off the remaining oxide using HF
- Back to bare wafer with n-well
- Subsequent steps involve similar series of steps



# Fab Step: Deposit Polysilicon

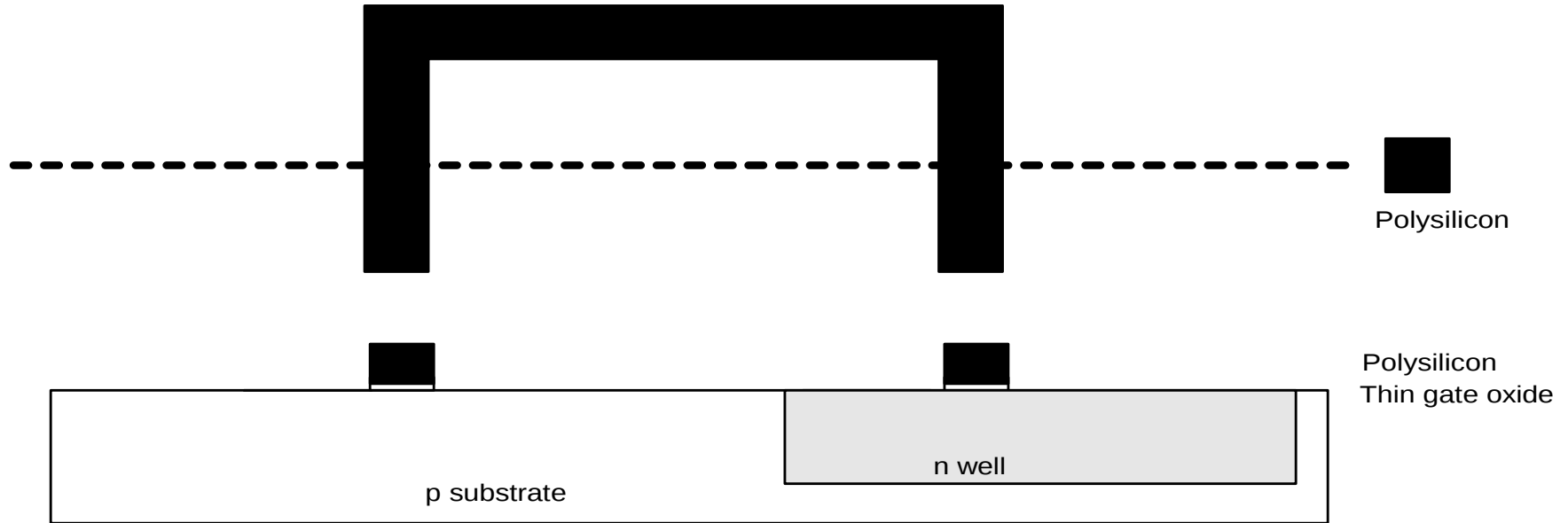
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- Deposit very thin layer of gate oxide
  - $< 20 \text{ \AA}$  (6-7 atomic layers)
- Chemical Vapor Deposition (CVD) of silicon layer
  - Place wafer in furnace with Silane gas ( $\text{SiH}_4$ )
  - Forms many small crystals called polysilicon
  - Heavily doped to be good conductor



# Fab Step: Polysilicon Patterning

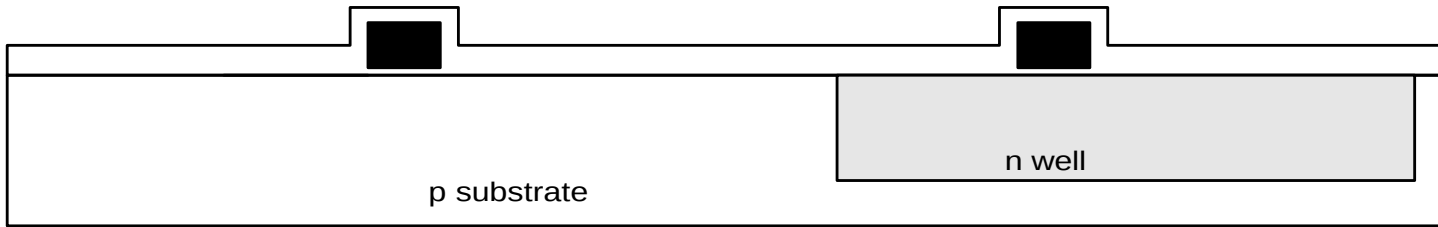
- Use same lithography process to pattern polysilicon



# Self-Aligned Process

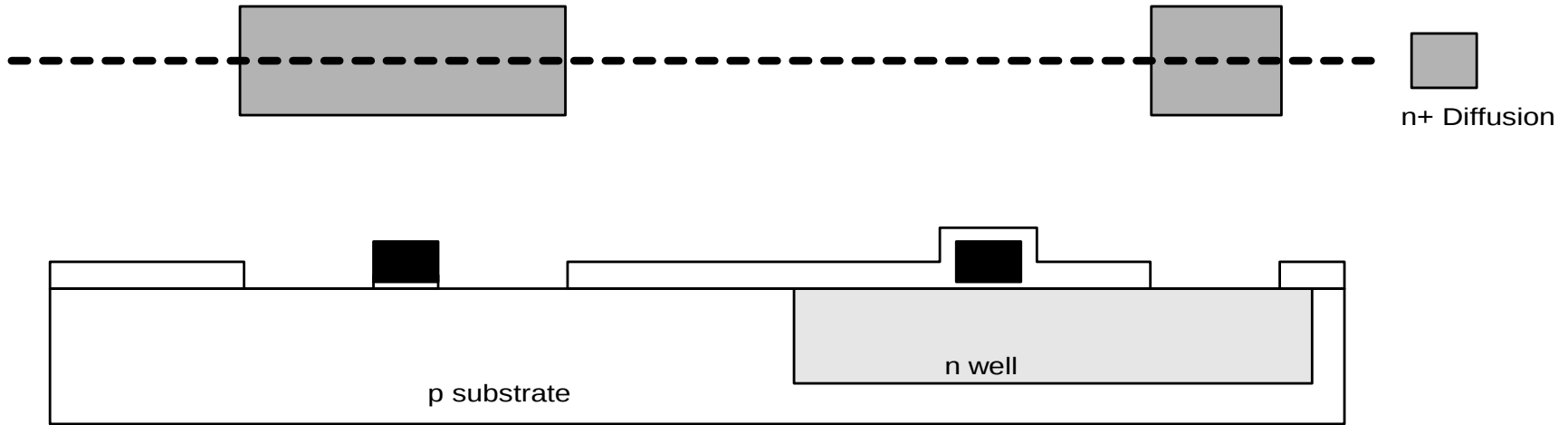
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- Use oxide and masking to expose where n<sup>+</sup> dopants should be diffused or implanted
- N-diffusion forms nMOS source, drain, and n-well contact



# Fab Step: Pattern N-Diffusion Areas

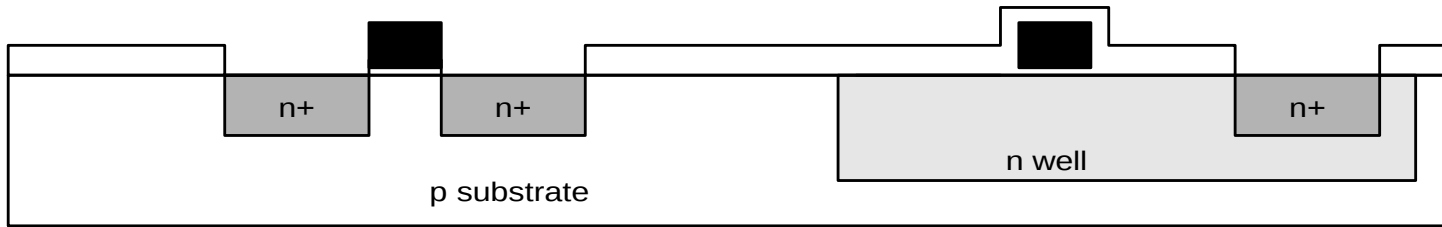
- Pattern oxide and form n+ regions
- *Self-aligned process* where gate blocks diffusion
- Polysilicon is better than metal for self-aligned gates because it doesn't melt during later processing



# Fab Step: Dope N-Diffusion Areas

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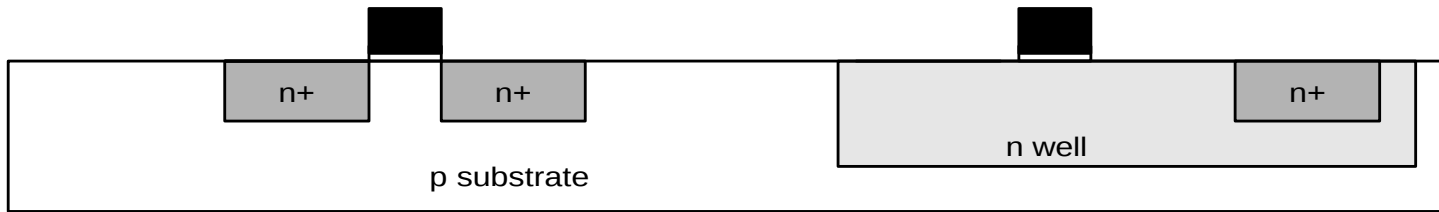
- Historically dopants were diffused
- Usually ion implantation today
- But regions are still called diffusion





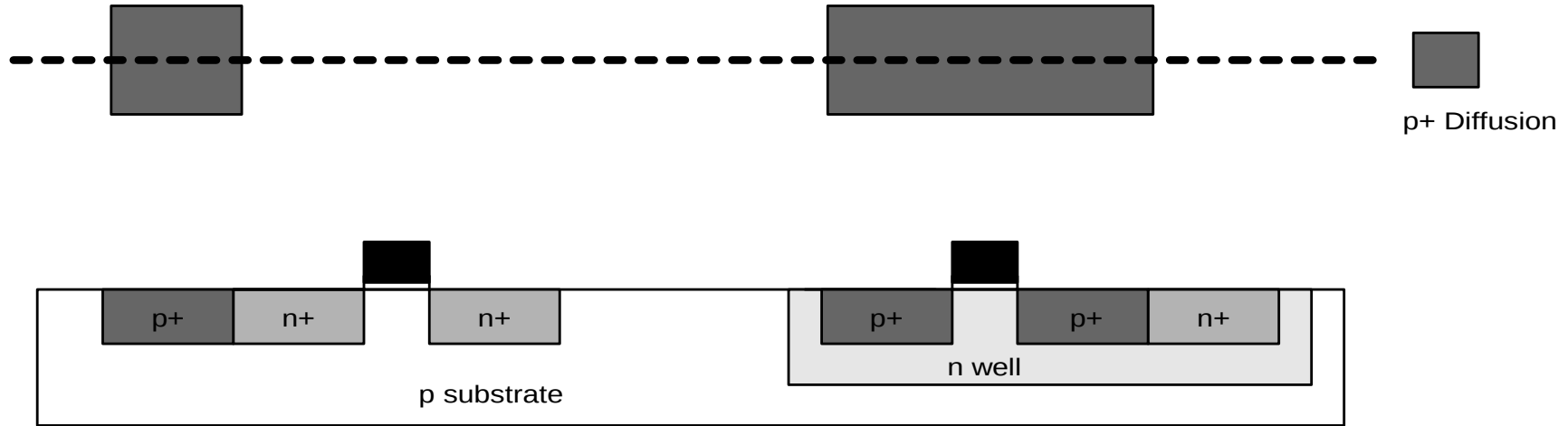
# Fab Step: Complete N-Diffusion

- Strip off oxide to complete patterning step



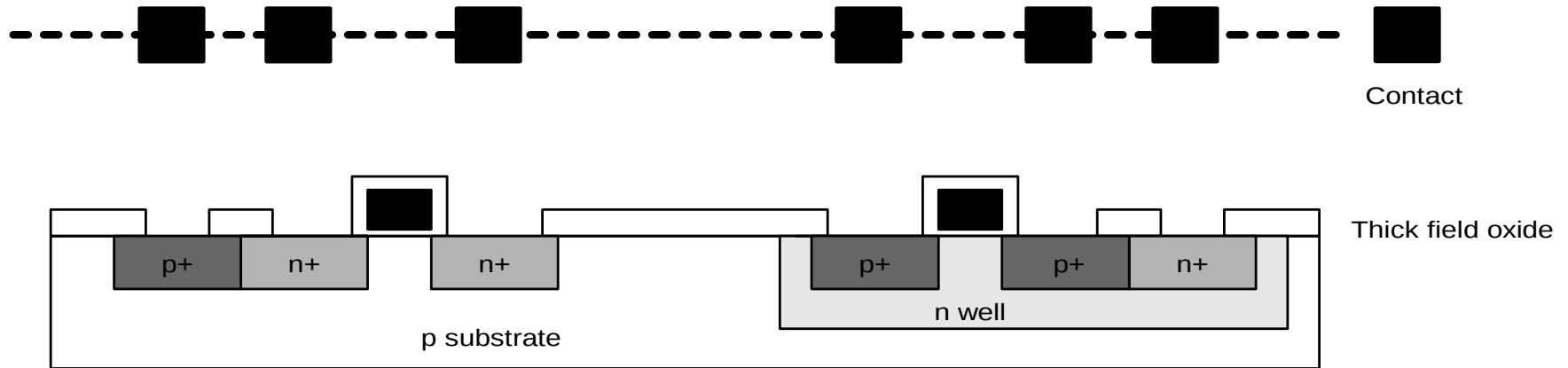
# Fab Steps: Repeat for P-Diffusion Areas

- Similar set of steps form p+ diffusion regions for pMOS source and drain and substrate contact



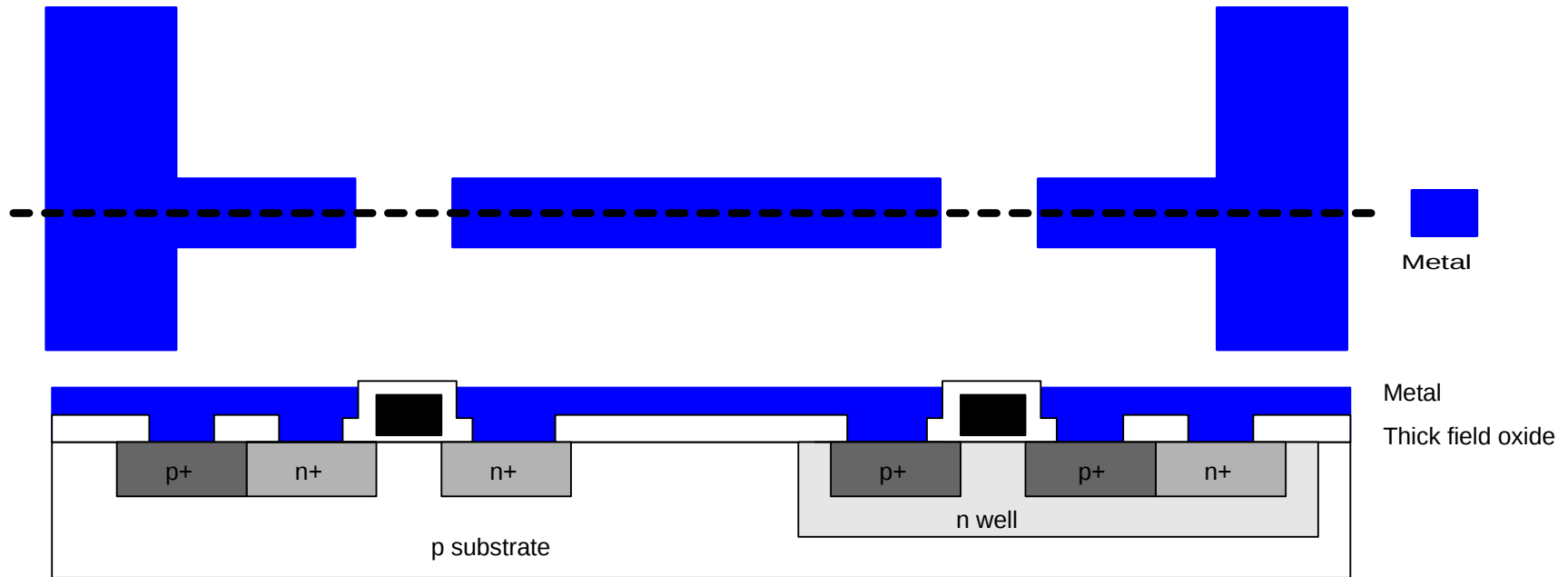
# Fab Step: Form Contacts

- Now we need to wire together the devices
- Cover chip with thick field oxide
- Etch oxide where contact cuts are needed



# Fab Step: Metalization

- Sputter on aluminum (or copper) over whole wafer
- Pattern to remove excess metal, leaving wires



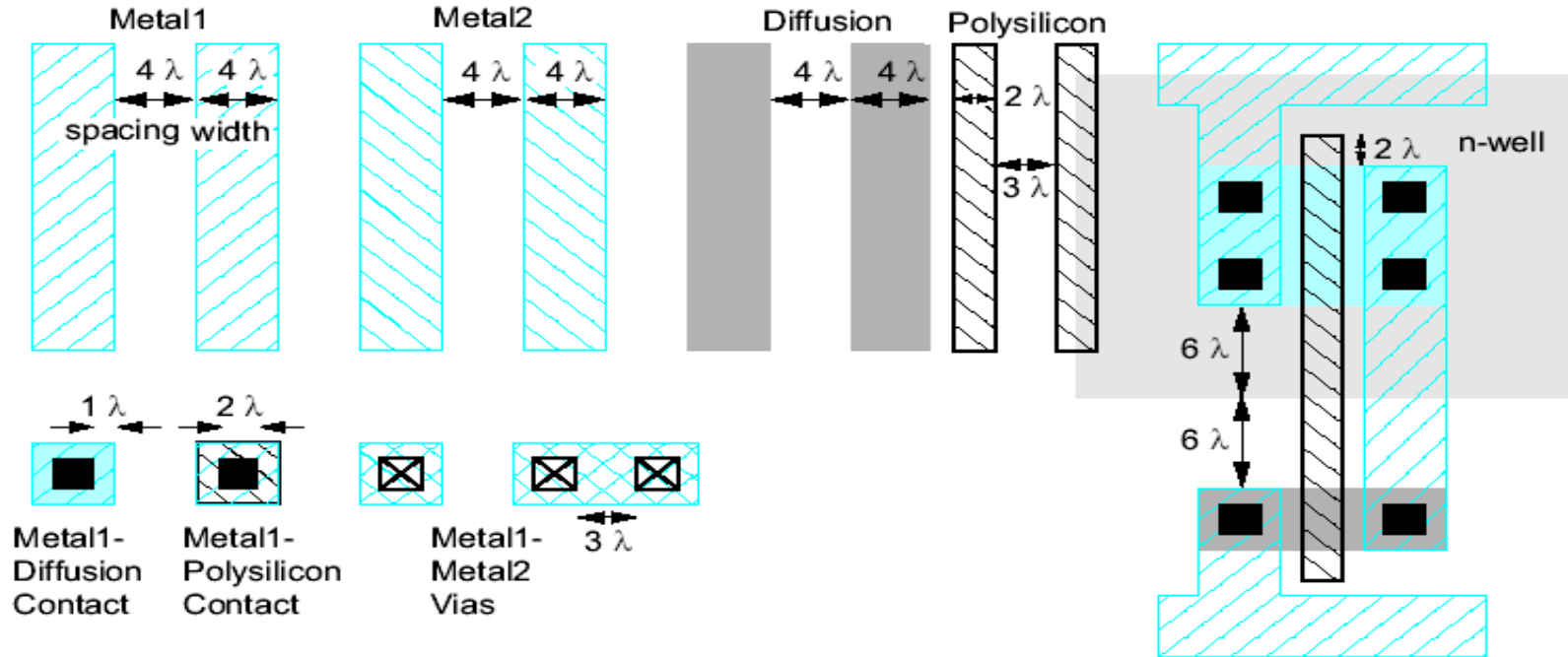
# Layout Considerations

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- Chips are specified with set of masks
- Minimum dimensions of masks determine transistor size (and hence speed, cost, and power)
- Feature size  $f$  = distance between source and drain
  - Set by minimum width of polysilicon
- Feature size improves 30% every 3 years or so
- Normalize for feature size when describing design rules
- Express rules in terms of  $\lambda = f/2$ 
  - E.g.  $\lambda = 0.3 \mu\text{m}$  in  $0.6 \mu\text{m}$  process

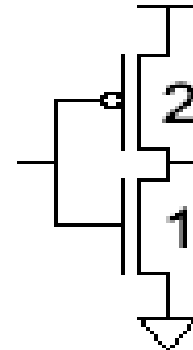
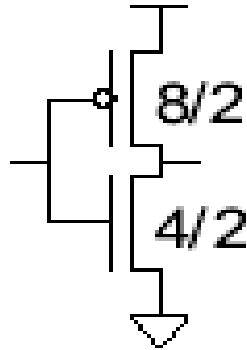
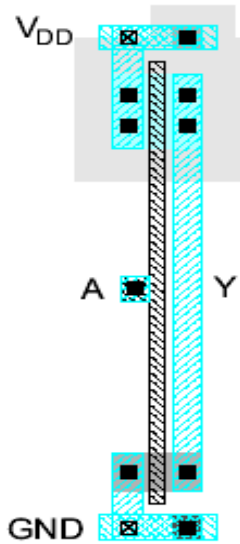
# Simplified Design Rules

- Conservative rules to get you started



# Example Inverter Layout

- Transistor dimensions specified as Width / Length
  - Minimum size is  $4\lambda / 2\lambda$ , sometimes called 1 unit
  - In  $f = 0.6 \mu\text{m}$  process, this is  $1.2 \mu\text{m}$  wide,  $0.6 \mu\text{m}$  long



# Summary

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- MOS Transistors are stack of gate, oxide, silicon
  - Can be viewed as electrically controlled switches
  - Build logic gates out of switches
  - Draw masks to specify layout of transistors
- 
- Now you know everything necessary to start designing schematics and layout for a simple chip!